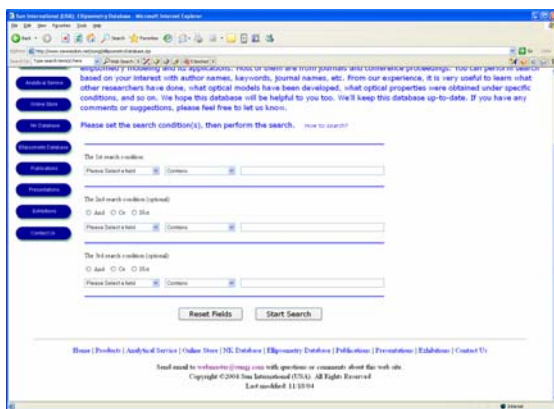


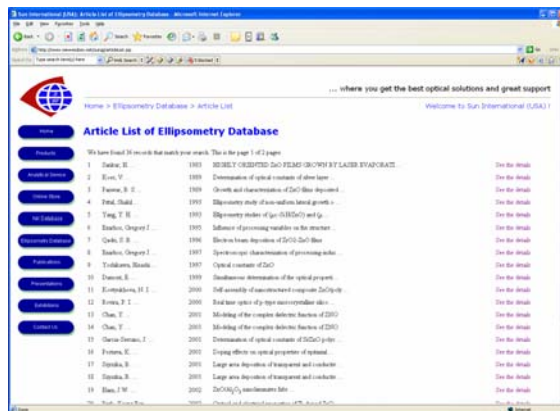
Introduction to Ellipsometry Database

We have collected over 8000 entries on ellipsometry related topics, such as instrumentation, ellipsometry principles, ellipsometry modeling and its applications. Most of them are from journals and conference proceedings. You can perform search based on your interest with author names, keywords, journal names, etc. From our experience, it is very useful to learn what other researchers have done, what optical models have been developed, what optical properties were obtained under specific conditions, and so on. We hope this database will be useful to you too. We'll keep this database up-to-date. You can visit our website www.angstec.com to feel free to use it. If you have any comments or suggestions, please let us know.

Search Input Interface



Search Results Output List



Entry Detail Output



Entry Detail Output

